

SYSTEM, METHOD, AND APPARATUS FOR FIELD SCANNING

ABSTRACT OF THE DISCLOSURE

A precision apparatus detects and displays two- and three-dimensional properties of electromagnetic fields emanating from a device under test (DUT). Electric, magnetic, electromagnetic (magnitude and direction), and other fields may be investigated either individually or in combination. A peak monitoring mode is also provided for determining a spectrum content figure of merit for the DUT. In an alternative embodiment, the susceptibility of the DUT to fields emanating from a nearby radiating source may be investigated.

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